

Notice of References Cited

Application/Control No.

10/655,850

Applicant(s)/Patent Under

Reexamination

WANG, WUN

Examiner

Elliot L Frank

Art Unit

2125

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U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|--------------------|----------------|
| | A | US-2002/0002415 A1 | 01-2002 | Mugibayashi et al. | 700/110 |
| | B | US-6,367,040 B1 | 04-2002 | Ott et al. | 714/724 |
| | C | US-6,496,958 B1 | 12-2002 | Ott et al. | 716/4 |
| | D | US-6,613,590 B2 | 09-2003 | Simmons, Steven J. | 438/14 |
| | E | US-6,717,431 B2 | 04-2004 | Rathei et al. | 324/765 |
| | F | US- | | | |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|--|
| | U | Patterson, O.D., Hansen, M.H., "The impact of tolerance on kill ratio estimation for memory", Advanced Semiconductor Manufacturing Conference and Workshop, 2000 IEEE/SEMI , 12-14 Sept. 2000, Pages:175 - 180 |
| | V | |
| | W | |
| | X | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.